

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

HEIN, REINHARD

Examiner

MOHAMED WASEL

Art Unit

2454

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,926,816 A	07-1999	Bauer et al.	707/8
*	B	US-2003/0120685 A1	06-2003	Duncombe et al.	707/200
*	C	US-2003/0140050 A1	07-2003	Li et al.	707/100
*	D	US-2003/0212681 A1	11-2003	Kasper, David J. II	707/9
*	E	US-2004/0068523 A1	04-2004	Keith et al.	707/200
*	F	US-6,725,262 B1	04-2004	Choquier et al.	709/221
*	G	US-2004/0153709 A1	08-2004	Burton-Krahn, Noel Morgen	714/004
*	H	US-6,944,623 B2	09-2005	Kim, Young-Eun	707/102
*	I	US-7,127,477 B2	10-2006	Duncombe et al.	707/203
*	J	US-2007/0038703 A1	02-2007	Tendjoukian et al.	709/206
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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